

| | | | | |
|-----------------------------------|--|---------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination SAKAI ET AL. | |
| | | Examiner Keath T. Chen | Art Unit 1709 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-5,709,757 | 01-1998 | Hatano et al. | 134/22.14 |
| * | B | US-5,252,133 | 10-1993 | Miyazaki et al. | 118/725 |
| * | C | US-2001/0024387 | 09-2001 | Raaijmakers et al. | 365/200 |
| * | D | US-RE36,328 | 10-1999 | Miyashita et al. | 427/255.23 |
| * | E | US-4,529,474 | 07-1985 | Fujiyama et al. | 134/1.1 |
| * | F | US-2001/0050054 | 12-2001 | Kwag et al. | 118/715 |
| * | G | US-2003/0049372 | 03-2003 | Cook et al. | 427/248.1 |
| * | H | US-6,146,461 | 11-2000 | Yang et al. | 118/715 |
| * | I | US-6,074,486 | 06-2000 | Yang et al. | 118/719 |
| * | J | US-2003/0213435 | 11-2003 | Okuda et al. | 118/724 |
| * | K | US-5,484,484 | 01-1996 | Yamaga et al. | 118/719 |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.